

Curriculum Vita of Collaborator: Prof Yamin Leprince-Wang

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Educational Qualification

HDR Université Marne-la-Vallée, France	2003
PhD, Université Pierre et Marie Curie, Paris, France	1995
MS Université Pierre et Marie Curie, Paris, France	1991
BS Zhejiang University, Hangzhou, China	1985

Professional Experience

Leader, Laboratoire de Physique des Matériaux Divisés et Interfaces (LPMDI, associated to CNRS)	2008-present
Chief of the Material Science Department	2006-2010
Professor, Université Paris-Est Marne-la-Vallée	2008-present
Associate Professor, Université Paris-Est Marne-la-Vallée	1996-2008
Assistant teacher, Université Paris-Est Marne-la-Vallée	1995

Selected/Related Publications

1. G. Vuye, S. Fisson, V. Nguyen Van, Y. Wang, J. Rivory and F. Abelès "Temperature dependence of the dielectric function of silicon using in situ spectroscopy ellipsometry" *Thin Solid Films*, 233 (1993) 166-170.
2. J. Rivory, S. Fisson, V. Nguyen Van, G. Vuye, Y. Wang, F. Abelès, and K. Yu-Zhang "Study of CaF₂ growth on Si, a-SiO₂ by in situ spectroscopic" *Thin Solid Films*, 233 (1993) 260-263.
3. Y. Wang, S. Fisson, V. Nguyen Van, G. Vuye, K. Yu-Zhang, J. Rivory "X-Ray photoelectron spectroscopy study of the growth of dielectric films on various substrates" *Surface and Coatings Technology*, 68/69 (1994) 724-728.
4. V. Nguyen Van, S. Fisson, J.-M. Frigério, J. Rivory, G. Vuye, Y. Wang, F. Abelès "Growth of low and high refractive index dielectric layers as studied by in situ ellipsometry" *Thin Solid Films*, 253 (1994) 257-261.
5. L. LEY, and Y. Wang, V. Nguyen Van, S. Fisson, D. Souche, G. Vuye, and J. Rivory "The initial stage in the formation of PtSi on Si(111) as followed by photoemission and spectroscopic ellipsometry" *Thin Solid Films*, 270 (1995) 561-566.
6. V. Nguyen Van, A. Brunet-Bruneau, S. Fisson, J.M. Frigério, G. Vuye, Y. Wang, F. Abelès, and J. Rivory "Determination of refractive index profiles by combining visible and IR ellipsometry measurements" *Applied Optics*, 35 (1996) 5540-5544.
7. Y. Leprince-Wang, K. Yu-Zhang, V. Nguyen Van, D. Souche and J. Rivory "Correlation between microstructure and the optical properties of TiO₂ thin films prepared on different substrates" *Thin Solid Films*, 307 (1997) 38-42.
8. K. Yu-Zhang, Y. Leprince-Wang "Microstructure study of non-epitaxial CaF₂ thin films grown on Si by transmission electron microscopy" *Materials Chemistry and Physics*, 52 (1998) 66-70.
9. Y. Leprince-Wang, D. Souche, K. Yu-Zhang, S. Fisson, G. Vuye and J. Rivory "Relations between the optical properties and microstructure of TiO₂ thin films prepared by ion-assisted deposition" *Thin Solid Films*, 359 (2000) 171-176.
10. F.Y. Yang, K. Liu, K.M. Hong, D.H. Reich, P.C. Searson, C.L. Chien, Y. Leprince-Wang, K. Yu-Zhang, K. Han, "Shubnikov de Haas oscillations in electrodeposited single crystal bismuth films" *Physical Review B*, 61 (2000) 6631-6636.
11. Y. Leprince-Wang, K. Yu-Zhang "Study of the growth morphology of TiO₂ thin films by AFM and TEM" *Surface and Coatings Technology*, 140 (2001) 155-160.
12. S. Pignard, K. Yu-Zhang, Y. Leprince-Wang, K. Han, H. Vincent, J.P. Senateur "Correlation between magnetoresistive properties and growth morphology of La_{0.8}MnO₃ thin films deposited on SrTiO₃, LaAlO₃ and MgO" *Thin Solid Films*, 391 (2001) p.21-27.
13. P. De Padova, R. Larciprete, C. Quaresima, R. Gunnella, A. Reginelli, L.Ferrari, P. Perfetti, K. Yu-Zhang, Y. Leprince-Wang "High resolution photoemission core level spectroscopy study and TEM analysis of the Ge/As/Si(001) growth" *Surface Science*, 482-485 (2001) 574-579.
14. D.P. Yu, Y.J. Xing, H.Y. Pan, M. Tence, Y. Leprince-Wang "Microstructural and Compositional Characterization of Silicon Carbide Nanocables Using Transmission Electron Microscopy", *Physica E: Low-dimensional Systems and Nanostructures*, 15 (2002) 1-5.